


<b>Search Notes</b>  	<b>Application/Control No.</b>  10764200	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Wiehe, Nathan	<b>Art Unit</b>  3745

SEARCHED			
Class	Subclass	Date	Examiner
415	186,189,208.1,209,211.2,213.1,214.1	5/28/2007	NEW
416	244R	5/28/2007	NEW
above	updated	10/18/2007	NEW

SEARCH NOTES			
Search Notes		Date	Examiner
415/186,189,208.1,209,211.2,213.1,214.1 416/244R Igor Kershteyn		5/28/2007	NEW
Text Search (See EAST Search History)		5/28/2007	NEW
Inventor Name Search		5/28/2007	NEW
above updated		10/18/2007	NEW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner